

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10/050,334	AGARWAL ET AL.
	Examiner	Art Unit
	Yennhu B Huynh	2813

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6,222,722	04-1999	Fukuzumi et al.	438/396
X	B	US-09/590795	06-2000	Agarwal et al.	438/496
X	C	US-6291289B2	09-2001	Rhodes et al.	438/239
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

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